



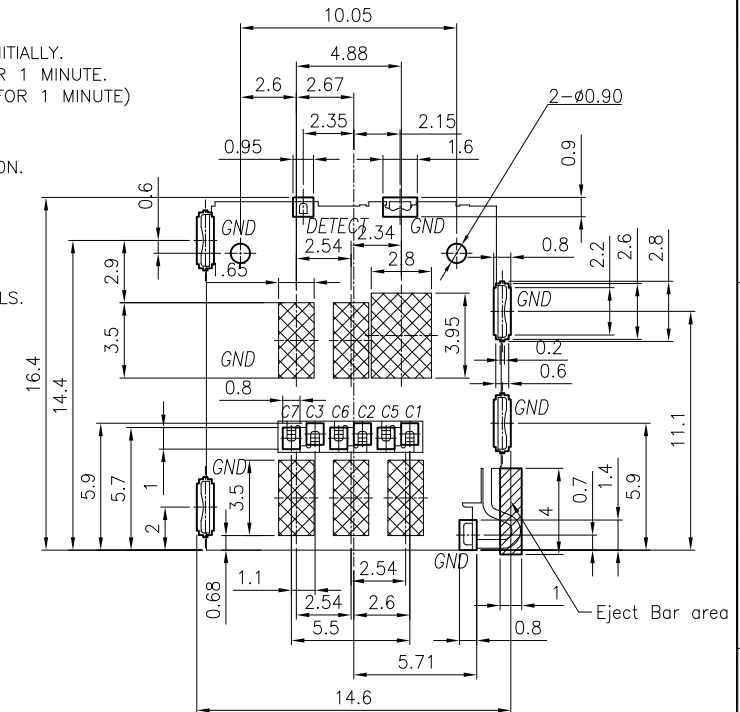
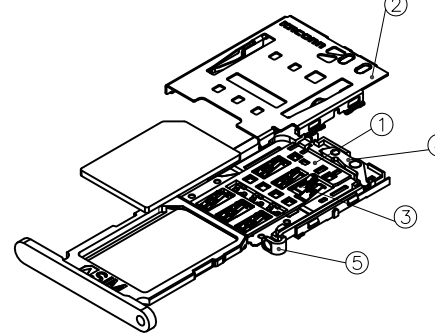
REV.	ECN NO OR DESCRIPTION	REVISED	DATE
△	PROPOSE ONLY	SIMON	2017.02.06

NOTES:

- ELECTRICAL CHARACTERISTICS:
 - CURRENT RATING: 1 Amp/PIN. MAX.
 - VOLTAGE: 30V DC. MAX.
 - LOW LEVEL CONTACT RESISTANCE: 30 mOhms MAX. INITIALLY.
 - DIELECTRIC WITHSTANDING VOLTAGE: 500V AC MIN. FOR 1 MINUTE.
 - INSULATION RESISTANCE: 100MOhms MIN.. (DC 500V FOR 1 MINUTE)
- MECHANICAL CHARACTERISTICS:
 - DURABILITY: 5000 CYCLES.
 - OPERATING FORCE (INSERTING & WITHDRAWAL): 1N-10N.
- ENVIRONMENTAL CHARACTERISTICS:
 - OPERATING TEMP. RANGE: -25°C TO 85°C.
 - STORAGE TEMP.: -40°C TO 85°C.
- QUANTITY OF PRODUCTS: 1000PCS/REEL MIN.
- PLEASE CONTACT KRCONN SALES TO VERIFY PRODUCT DETAILS.
- PART No.:

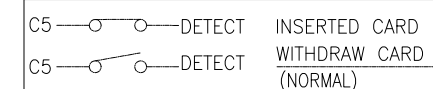
SIM SERIES
1=WITH POST
Push Lever
15:HEIGHT 1.5mm

S 1 PL - 15 00 06- 29 G
G=gold flash
29=Product Order
Pin NO. 06=6Pin
00=NORMAL TYPE.



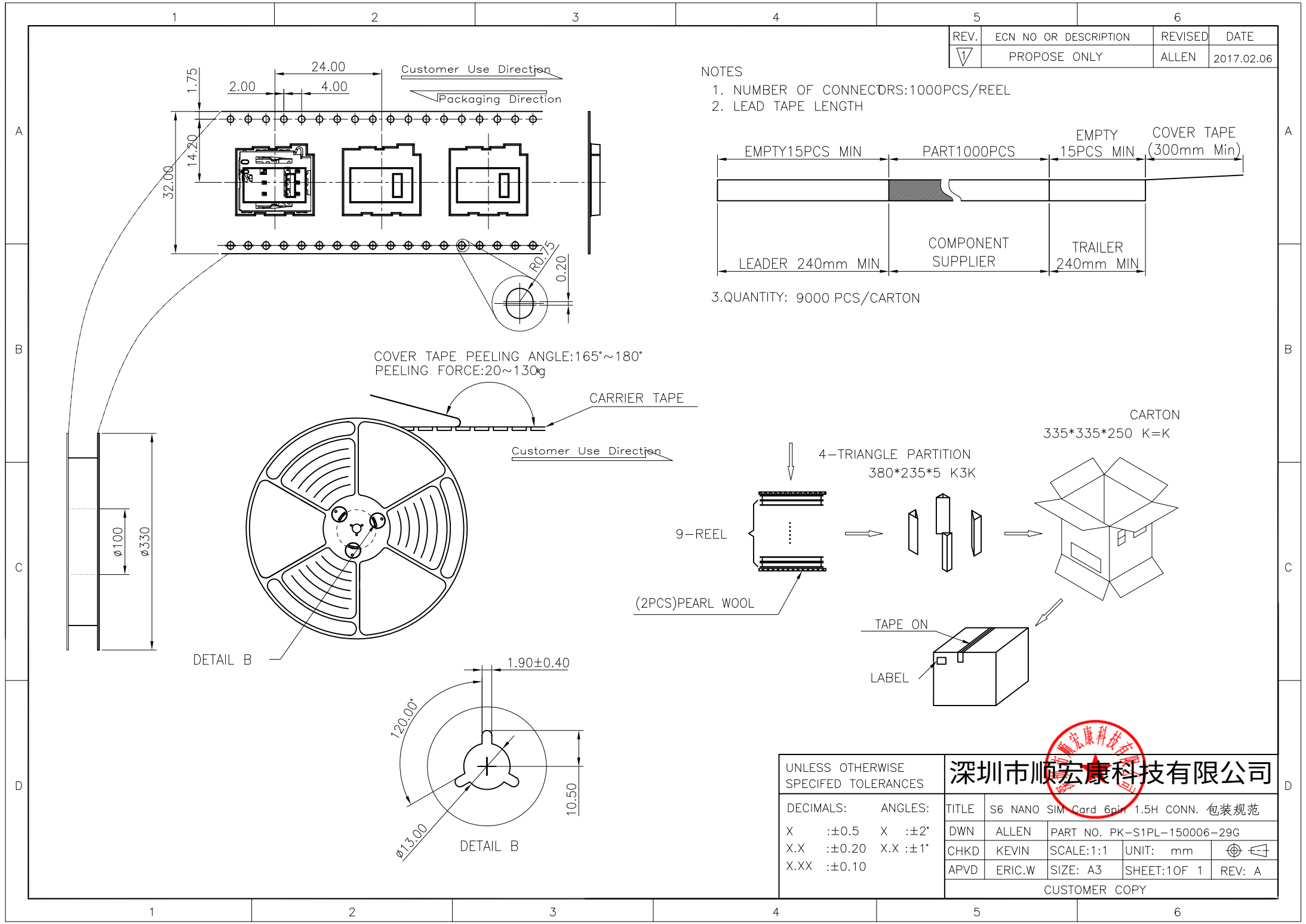
Recommended PCB Layout (General tolerance:±0.05) NO WITING AREA

Circuit Diagram For Switch



⑤	LEVER	1	STAINLESS STEEL	NO PLATING
④	CAM	1	STAINLESS STEEL	NO PLATING
③	TERMINAL	6	COPOER ALLOY	CONTACT Au OVER ALL:
②	SHELL	1	STAINLESS STEEL	Ni/Au PLATING
①	BODY HOUSING	1	THERMOPLASTIC	UL 94V-0
NO.	DESCRIPTION	QT'Y	MATERIAL	NOTE
UNLESS OTHERWISE SPECIFIED TOLERANCES				
DECIMALS:	ANGLES:	TITLE		
X :±0.5	X :±2°	S6 NANO SIM Card 6pin 1.5H CONN. (SMT)		
X.X :±0.20	X.X :±1°	DWN	JOHNLE	PART NO. S1PL-150006-29G
X.XX :±0.10		CHKD	KEVIN.D	SCALE:1:1 UNIT: mm
		APVD	SIMON.M	SIZE: A4 SHEET:1OF 1 REV: A
CUSTOMER COPY				

深圳市顺宏康科技有限公司



文件名稱 DOCUMENT NAME:	主題 SUBJECT :	文件編號 DOCUMENT NO:	
PRODUCT SPECIFICATION	SPEC for PUSH LEVER NANO SIM	S1PL-150006-29G	
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	APPROVED	CHECKED	PREPARED	ISSUED BY: King Hsu
BY	Kevin	Allen	King Hsu	
DATE				

文件名稱 DOCUMENT NAME: PRODUCT SPECIFICATION	主題 SUBJECT : SPEC for PUSH LEVER NANO SIM	文件編號 DOCUMENT NO: S1PL-150006-29G	
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1. SCOPE

This product specification defines the product performance and the test methods to ascertain the performance of the 1.5H PUSH LEVER NANO SIM card Connector, which is designed and manufactured by **KRCONN** international Inc.

2. REFERENCE DOCUMENTS

MIL-STD-1344A	Test method for electrical connector
MIL-STD-202F	Test method for electrical components
EIA364	Test method for electrical components
JIS C 5402	Test method for electrical components
MIL-G-45204C	Specification for gold plating
IEC 60512-5-1	IEC standard for current carrying capacity tests
IEC 60068	Specification for tin plating
UL94	UL standard for safety of attachment plug and receptacle

3. FEATURE & DIMENSIONS

3.1. PRODUCT DIMENSION

This connector shall have the dimensions as shown in Customer Drawing.

3.2. PCB/PANEL LAYOUT

The recommended PCB layout are shown in Customer Drawing.

3.3. BILL OF MATERIAL

The bill of material and product number are described in Customer Drawing

3.4. MECHANICAL & ELECTRICAL CHARACTERISTIC

The connector shall have the mechanical and electrical performance as described in Customer Drawing

3.5. PACKAGING

Parts shall be packaged according to requirements specified in purchase order for safe delivery. Parts required tape and reel should meet the proper specification per purchase order.

3.6. MARKING

Mark of manufacturer's name, industry recognized logo, or customer approved marks.

4. Environmental

- 4.1 Rated current: 0.5A Max./Pin
- 4.2 Rated voltage: 10V Max.
- 4.3 Operating temperature: -40℃ to +85℃
- 4.4 Operating humidity: 55℃ / 95%RH Max.(non-condensing)
- 4.5 Shipping and storage temperature: -5℃ to +40℃
- 4.6 Shipping and storage Humidity: 10% to 80%

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4.7 Solder-ability:

Connectors meet solder-ability to IEC 60512-5-1. Finish shall be free of contaminants. Peak temperature in soldering interval is 260℃ for a Maximum of 10 seconds.

5. PERFORMANCE AND TEST DESCRIPTION

5.1. REQUIREMENT

5.1.1 Conformation of Product

Test Method/Condition	Requirements
Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.

5.1.2. Mechanical Characteristics

5.1.2.1 Terminal Normal Force

Test Method/Condition	Requirements
Measure until that 0.1mm clearance between the jig and the housing is movable. (speed: 25±3mm/min)	20g to 70g/Pin.

5.1.2.2 Terminal Retention Force

Test Method/Condition	Requirements
Apply perpendicular pull out force at the speed rate of 25±3mm/min	1.2N Min/Pin.

5.1.2.3 Soldering Strength

Test Method/Condition	Requirements
PCBA mount, applying force the entrance of socket in positive direction at the speed rate of 25±3 mm / minute.	10Kg Min

5.1.2.4 Push Strength

Test Method/Condition	Requirements
The tray is inserted in positive direection and the load of 2Kgf is added for 20S at the speed rate of 25±3 mm / minute.	No evidence of damage

5.1.2.5 Tray Insertion & Removal Force

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Test Method/Condition	Requirements
Tray insertion Force: (Speed:25±3mm/min) Card is measuring the force when inserting the insertion tray on socket	10N Max.
Tray removal Force: (Speed:25±3mm/min) Card is measuring the force when removing the embedded tray from socket	3N Min
Lever Push Force: (Speed:25±3mm/min) Measure the force when card is inserted, remove the tray;	15N Max.

5.1.2.6 Durability

Test Method/Condition	Requirements
Nano SIM Card Repeated mate & un-mate Use to Actual card(Not Cut by Manual) Repeated mate and unmate connector for 5000 cycles. Operation Speed: 500 cycles/Hr Every 10 cycles blow with dry air for 3secs Every 500 cycles have shorten rest time	1. No evidence of damage 2.contact resistance Change 40 mΩ MAX
Tray Repeated mate & un-mate Mate and unmate connector for 1000 cycles. Operation Speed : 500 cycles/Hr Every 10 cycles blow with dry air for 3secs	1. No evidence of damage 2.contact resistance Change 40 mΩ MAX

5.1.2.7 Vibration

Test Method/Condition	Requirements
MIL-STD-202, Method 201, Mate dummy card applying each terminal shall be connected in series and then 0.1A DC shall be applied. Amplitude: 1.5 mm Frequency: 10-55-10 Hz Traversed in 1 minute For 2 hours each of 3 mutually perpendicular plane, 1 mA DC	1.Without mechanical damage and electrical discontinuity greater then 1 μsec (s) shall occur. 2.contact resistance Change 40 mΩ MAX

5.1.2.8. Shock

Test Method/Condition	Requirements
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MIL-STD-202, Method 213, Mate dummy card and subject to the following shock conditions: 50 G's semi-sine shock pulse off 11-millisecond duration; 3 times shocks in each direction applied planes.	1.No electrical discontinuity greater than 1 μ sec. shall occur. 2.contact resistance Change 40 m Ω MAX
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5.1.3 Electrical Characteristics:

5.1.3.1 Low Level Contact Resistance

Test Method/Condition	Requirements
IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	100 m Ω MAX.

5.1.3.2 Insulation Resistance

Test Method/Condition	Requirements
MIL-STD-202, Method 302, Apply 500V DC between adjacent pins or pin and ground.	1000 M Ω minimum.

5.1.3.3 Dielectric Withstanding Voltage

Test Method/Condition	Requirements
MIL-STD-202, Method 301, Apply 500V AC for 1 minute between adjacent terminals and ground.	No breakdown.

5.1.4 Environmental Characteristics:

5.1.4.1 Temperate Rasing

Test Method/Condition	Requirements
UL 498 / IEC 60512-5-1,test 5a Measure the remperature rising by probing on soldered ares of terminal, after the temperature becomes stabilized deduct ambient temperature from the measured value. Carrying rated current load for 2Hr	Variation 30°C Max.

5.1.4.2 Thermal Shock

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Test Method/Condition	Requirements
MIL-STD-202, Method 107 Subject mated connector to 10 cycles between $-55 \pm 3^{\circ}\text{C}$ / 30 minutes and $+85 \pm 3^{\circ}\text{C}$ / 30 minutes	1.No evidence of damage 2.contact resistance Change 40 mΩ MAX 3.Dielectric Withstanding Voltage meet Requirement,

5.1.4.2 High temperature resistance

Test Method/Condition	Requirements
Mate dummy card and exposed to $85 \pm 3^{\circ}\text{C}$ for 96 hours. It shall be maintained at standard atmospheric condition for 30 min after measurement shall be made.	1.No evidence of damage 2.contact resistance Change 40 mΩ MAX 3.Dielectric Withstanding Voltage meet Requirement,

5.1.4.3 Low temperature resistance

Test Method/Condition	Requirements
Mate dummy card and exposed to $-40 \pm 3^{\circ}\text{C}$ for 96 hours. It shall be maintained at standard atmospheric condition for 30 min after measurement shall be made.	1.No evidence of damage 2.contact resistance Change 40 mΩ MAX 3.Dielectric Withstanding Voltage meet Requirement,

5.1.4.4 Humidity test

Test Method/Condition	Requirements
IEC 512-6-1 1I, IEC 68-2-56- Test Db Temperature: 85°C Relative Humidity: 85% Duration: 120Hr After Test return to ambient temp. for 2 Hr	1.No evidence of damage 2.contact resistance Change 40 mΩ MAX 3.Dielectric Withstanding Voltage meet Requirement,

5.1.4.5 Salt Spray

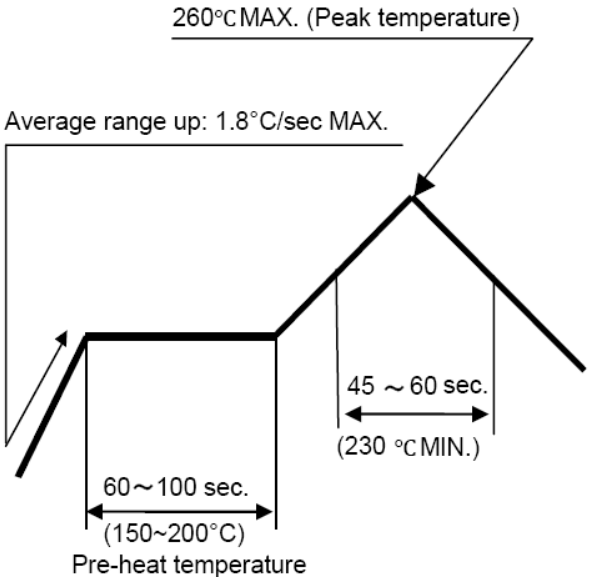
Test Method/Condition	Requirements
JIS C5028/MIL-STD-202, Method 101D NaCl solution Concentration: $5 \pm 1\%$ Duration: 48 hours Ambient Temperature: $35 \pm 3^{\circ}\text{C}$.	1.No evidence of damage 2.contact resistance Change 40 mΩ MAX .

5.1.4.6 Solder-ability

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Test Method/Condition	Requirements
IEC 60068-2-54 Solder temp. 255 ± 5 °C Immersion time: 5 ± 0.5 sec.	Minimum solder wetting: 95% of immersion area.

5.1.4.7 Resistance to Soldering Heat

Test Method/Condition	Requirements
EIA-364-56 Temp. 230-260 °C. Max time for 60 ± 0.5 sec. Peak temp. $260 +0/-5$ °C. Max time for 10 ± 0.5 sec. 	No evidence of damage

5.2. TEST CONDITION

Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

5.3. SAMPLE SELECTION

Test samples shall be selected at random from current production. No test samples shall be reused. Samples are pre-conditioned with 3 cycles of durability. Each group shall be containing 5 test samples.

5.4. TEST SEQUENCE

Products qualification test sequence as shown in Table .

Test Description	Test Group and Sequence							
	A	B	C	D	E	F	G	H
Conformation of Product	1	1,7	1,5	1	1,6	1,6	1,4	1,3
Terminal Normal Force	2							
Terminal Retention Force	3							
Soldering Strength		9						
Push Strength			7					
Tray Insertion & Removal Force		5						
Durability		6						
Vibration			3					
Shock			4					
Low level contact resistance		2,8	2,6		2,7	2,7	2,5	
Insulation Resistance		3						
Dielectric Withstanding Voltage		4			3,8	3,8		
Temperate Rasing				2				
Heat shock					4			
High temperature resistance						4		
Low temperature resistance						5		
Humidity test					5			
Salt Spray							3	
Solder ability								4
Resistance to Soldering Heat								2
Sample size	N=5	N=5	N=5	N=5	N=5	N=5	N=5	N=5

信賴性測試報告

Reliability Test Report

產品規格/Part Name: 1.5H PUSH
LEVER Nano SIM

產品料號/Part NO.: S1PL-150006-29G(S6)

送檢日期/Send Date: 2016-10-27

送檢部門/Require Dep't: 工程部

測試部門/Test Dep't: 品保

測試時間/Test Date: 2016/11/28-11/7

1. 測試目的 Purpose

Evaluate the electronocal,mechanical and environmental characteristics of SIM connector.

2. 測試條件 Test requirement and condition

測試參數/Parameter	規格要求/Requirement	測試參數/Parameter	規格要求/Requirement
參考文件/Ref.	NS0DD-140006-10G	儲存濕度/Storage Humidity	55°C /80%RH max.
額定電壓/Voltage	10 V DC Max	儲存溫度/Storage Temperature	-5°C to +40°C
額定電流/Rating Current	0.5A Per Pin	工作溫度/Operating Temperature	-40°C to+85°C

3. 測試順序 Test Sequence

Products qualification test sequence as shown in Table

Test Description	Test Group and Sequence							
	A	B	C	D	E	F	G	H
Conformation of Product	1	1,7	1,5	1	1,6	1,6	1,4	1,3
Terminal Normal Force	2							
Terminal Retention Force	3							
Soldering Strength		9						
Push Strength			7					
Tray Insertion & Removal Force		5						
Durability		6						
Vibration			3					
Shock			4					
Low level contact resistance		2,8	2,6		2,7	2,7	2,5	
Insulation Resistance		3						
Dielectric Withstanding Voltage		4			3,8	3,8		
Temperate Rasing				2				
Thermal Shock					4			
High temperature resistance						4		
Low temperature resistance						5		
Humidity test					5			
Salt Spray							3	
Solder ability								4
Resistance to Soldering Heat								2
Sample size	5pcs	5pcs	5pcs	5pcs	5pcs	5pcs	5pcs	5pcs

4. 測試方法與結果 Test Methods & Result

備 註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): JE Long

審核(Check): Sean Long

測試(Test): Joe Bai

信賴性測試報告

Reliability Test Report

產品規格/Part Name: 1.5H PUSH LEVER Nano SIM

產品料號/Part NO.: S1PL-150006-29G(S6)

送檢日期/Send Date: 2016-10-27

送檢部門/Require Dep't: 工程部

測試部門/Test Dep't: 品保

測試時間/Test Date: 2016/11/28-11/7

4.1 Test Group A

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements				結論/Conclusion
Conformation of Product	Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.				PASS
Terminal Normal Force	Measure until that 0.1mm clearance between the jig and the housing is movable. (spped: 25±3mm/min)	20-70gf				PASS
		Result (gf)	Min	Max	Average	
			41.0	58.2	54.7	
Terminal Retention Force	Apply perpendicular pull out force at the spped rate of 25±3mm/min	1.2N				PASS
		Result (N)	Min	Max	Average	
			1.97	4.26	3.52	

4.2 Test Group B

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements				結論/Conclusion
Conformation of Product	Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.				PASS
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	100mΩ Max.				PASS
		Result (mΩ)	Min	Max	Average	
			14.6	25.7	16.2	
Insulation Resistance	MIL-STD-202, Method 302, Apply 500V DC between adjacent pins or pin and ground.	1000MΩ Min				PASS
		Result	Min	Max	Average	
			PASS	PASS	PASS	
Dielectric Withstanding Voltage	MIL-STD-202, Method 301, Apply 500V AC for 1 minute between adjacent terminals and ground.	No evidence of damage				PASS
Tray Insertion & Removal Force	Card is measuring the force when inserting and removal tray on socket	Insertion force:10N Max.Removal force:3N Min				PASS
		Result (N)	Min	Max	Average	
		Insertion	3.11	4.52	3.98	
		Removal	4.25	7.27	6.08	
Lever Push Force	Measure the force when card is inserted, remove the the tray;	15N Max				PASS
		Result (N)	Min	Max	Average	
			10.80	12.54	11.29	
SIM Card Durability	Use to Actual card(Not Cut by Manual) Repeated mate and unmate connector for 5000 cycles. Operation Speed: 500 cycles/Hr Every 10 cycles blow with dry air for 3secs Every 500 cycles have shorten rest time	No evidence of damage				PASS

核定(Approval) JE Long

審核(Check): Sean Long

測試(Test): Joe Bai

信賴性測試報告

Reliability Test Report

產品規格/Part Name: 1.5H PUSH LEVER Nano SIM

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送檢日期/Send Date: 2016-10-27

送檢部門/Require Dep't: 工程部

測試部門/Test Dep't: 品保

測試時間/Test Date: 2016/11/28-11/7

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements				結論/Conclusion
Tray Durability	Mate and unmate connector for 1000 cycles. Operation Speed : 500 cycles/Hr	No evidence of damage				PASS
Conformation of Product	Visually, functionally inspected per applicable product drawing.	No evidence of damage				PASS
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	Change 40 mΩ MAX				PASS
		Result Δ (mΩ)	Min 2.12	Max 7.89	Average 5.34	
Soldering Strength	PCBA mount, applying force the entrance of socket in positive direction at the speed rate of 25±3 mm / minute.	10Kg Min				PASS
		Result(Kgf)	Min	Max	Average	
		X-axis	12.56	14.25	13.48	
		Y-axis	18.72	25.31	23.57	

4.3 Test Group C

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements				結論/Conclusion
Conformation of Product	Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.				PASS
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	100mΩ Max.				PASS
		Result (mΩ)	Min 11.35	Max 25.13	Average 15.21	
Vibration	MIL-STD-202, Method 201, Mate dummy card applying each terminal shall be connected in series and then 0.1A DC shall be applied. Amplitude: 1.5 mm Frequency: 10-55-10 Hz Traversed in 1 minute For 2 hours each of 3 mutually perpendicular plane, 1 mA DC	Without mechanical damage and electrical discontinuity greater then 1 μsec (s) shall occur.				PASS
		Result (mΩ)	Min OK	Max OK	Average OK	
Shock	MIL-STD-202, Method 213, Mate dummy card and subject to the following shock conditions: 50 G's semi-sine shock pulse off 11-millisecond duration; 3 times shocks in each direction applied planes.	No electrical discontinuity greater than 1 μsec. shall occur.				PASS
		Result (mΩ)	Min OK	Max OK	Average OK	
Conformation of Product	Visually, functionally inspected per applicable product drawing.	No evidence of damage				PASS
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	Change 40 mΩ MAX				PASS
		Result Δ (mΩ)	Min 0.28	Max 5.74	Average 4.26	

核定(Approval) JE Long

審核(Check): Sean Long

測試(Test): Joe Bai

信賴性測試報告

Reliability Test Report

產品規格/Part Name: 1.5H PUSH LEVER Nano SIM

產品料號/Part NO.: S1PL-150006-29G(S6)

送檢日期/Send Date: 2016-10-27

送檢部門/Require Dep't: 工程部

測試部門/Test Dep't: 品保

測試時間/Test Date: 2016/11/28-11/7

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements	結論/Conclusion
Push Strength	The tray is inserted in positive direection and the load of 2Kg _f is added for 20S at the speed rate of 25±3 mm / minute.	No evidence of damage	PASS

4.4 Test Group D

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements	結論/Conclusion								
Conformation of Product	Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.	PASS								
Temperate Rasing	UL 498 / IEC 60512-5-1, test 5a Measure the remperature rising by probing on soldered ares of terminal, after the temperature becomes stabilized deduct ambient temperature from the measured value. Carrying rated current load for 2Hr	Variation 30℃ Max. <table><tr><td>Result (℃)</td><td>Min</td><td>Max</td><td>Average</td></tr><tr><td></td><td>2.00</td><td>4.90</td><td>3.26</td></tr></table>	Result (℃)	Min	Max	Average		2.00	4.90	3.26	PASS
Result (℃)	Min	Max	Average								
	2.00	4.90	3.26								

4.5 Test Group E

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements	結論/Conclusion								
Conformation of Product	Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.	PASS								
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	100mΩ Max. <table><tr><td>Result (mΩ)</td><td>Min</td><td>Max</td><td>Average</td></tr><tr><td></td><td>12.47</td><td>25.71</td><td>15.21</td></tr></table>	Result (mΩ)	Min	Max	Average		12.47	25.71	15.21	PASS
Result (mΩ)	Min	Max	Average								
	12.47	25.71	15.21								
Dielectric Withstanding Voltage	MIL-STD-202, Method 301, Apply 500V AC for 1 minute between adjacent terminals and ground.	No evidence of damage	PASS								
Thermal Shock	MIL-STD-202, Method 107 Subject mated connector to 10 cycles between -55 ± 3 °C / 30 minutes and +85 ± 3 °C / 30 minutes	No evidence of damage	PASS								
Humidity test	IEC 512-6-1 1I, IEC 68-2-56- Test Db Temperature: 85 °C Relative Hunmidity: 85% Duration: 120Hr After Test return to ambient temp. for 2 Hr	No evidence of damage	PASS								
Conformation of Product	Visually, functionally inspected per applicable product drawing.	No evidence of damage	PASS								
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	Change 40 mΩ MAX <table><tr><td>Result Δ (mΩ)</td><td>Min</td><td>Max</td><td>Average</td></tr><tr><td></td><td>1.12</td><td>6.16</td><td>2.75</td></tr></table>	Result Δ (mΩ)	Min	Max	Average		1.12	6.16	2.75	PASS
Result Δ (mΩ)	Min	Max	Average								
	1.12	6.16	2.75								

核定(Approval) JE Long

審核(Check): Sean Long

測試(Test): Joe Bai

信賴性測試報告

Reliability Test Report

產品規格/Part Name: 1.5H PUSH LEVER Nano SIM

產品料號/Part NO.: S1PL-150006-29G(S6)

送檢日期/Send Date: 2016-10-27

送檢部門/Require Dep't: 工程部

測試部門/Test Dep't: 品保

測試時間/Test Date: 2016/11/28-11/7

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements	結論/Conclusion
Dielectric Withstanding Voltage	MIL-STD-202, Method 301, Apply 500V AC for 1 minute between adjacent terminals and ground.	No evidence of damage	PASS

4.6 Test Group F

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements	結論/Conclusion								
Conformation of Product	Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.	PASS								
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	100mΩ Max. <table><tr><td>Result (mΩ)</td><td>Min</td><td>Max</td><td>Average</td></tr><tr><td></td><td>12.35</td><td>24.94</td><td>15.66</td></tr></table>	Result (mΩ)	Min	Max	Average		12.35	24.94	15.66	PASS
Result (mΩ)	Min	Max	Average								
	12.35	24.94	15.66								
Dielectric Withstanding Voltage	MIL-STD-202, Method 301, Apply 500V AC for 1 minute between adjacent terminals and ground.	No breakdown.	PASS								
High temperature resistance	Mate dummy card and exposed to $85 \pm 3^{\circ}\text{C}$ for 96 hours. It shall be maintained at standard atmospheric condition for 30 min after measurement shall be made.	No evidence of damage	PASS								
Low temperature resistance	Mate dummy card and exposed to $-40 \pm 3^{\circ}\text{C}$ for 96 hours. It shall be maintained at standard atmospheric condition for 30 min after measurement shall be made.	No evidence of damage	PASS								
Conformation of Product	Visually, functionally inspected per applicable product drawing.	No evidence of damage	PASS								
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	Change 40 mΩ MAX <table><tr><td>Result Δ (mΩ)</td><td>Min</td><td>Max</td><td>Average</td></tr><tr><td></td><td>0.78</td><td>7.24</td><td>3.88</td></tr></table>	Result Δ (mΩ)	Min	Max	Average		0.78	7.24	3.88	PASS
Result Δ (mΩ)	Min	Max	Average								
	0.78	7.24	3.88								
Dielectric Withstanding Voltage	MIL-STD-202, Method 301, Apply 500V AC for 1 minute between adjacent terminals and ground.	No evidence of damage	PASS								

4.7 Test Group G

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements	結論/Conclusion
Conformation of Product	Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.	PASS

核定(Approval) JE Long

審核(Check): Sean Long

測試(Test): Joe Bai

信賴性測試報告

Reliability Test Report

產品規格/Part Name: 1.5H PUSH LEVER Nano SIM 產品料號/Part NO.: S1PL-150006-29G(S6) 送檢日期/Send Date: 2016-10-27
送檢部門/Require Dep't: 工程部 測試部門/Test Dep't: 品保 測試時間/Test Date: 2016-11-15

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements				結論/Conclusion
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	100mΩ Max.				PASS
		Result (mΩ)	Min	Max	Average	
			11.58	26.42	16.25	
Salt Spray	JIS C5028/MIL-STD-202, Method 101D NaCl solution Concentration: 5±1% Duration: 48 hours Ambient Temperature: 35 ± 3 °C.	No evidence of damage				PASS
Conformation of Product	Visually, functionally inspected per applicable product drawing.	No evidence of damage				PASS
Low Level Contact Resistance	IEC 60512-2-1 / JIS C 5402 5.4, Mate dummy card, measure by dry circuit, 20mV MAX, 10mA MAX.	Change 40 mΩ MAX				PASS
		Result Δ (mΩ)	Min	Max	Average	
			0.98	6.24	2.55	

4.8 Test Group H

測試項目/ Item	測試方法/Test Methods	測試要求/ Requirements	結論/Conclusion
Conformation of Product	Visually, functionally inspected per applicable product drawing.	Product shall be conforming to the requirements of applicable product drawing.	PASS
Resistance to Soldering Heat	EIA-364-56 Temp. 230-260 °C. Max time for 60 ± 0.5 sec. Peak temp.260 +0/-5°C.Max time for 10± 0.5 sec.	Product shall be conforming to the requirements of applicable product drawing.	PASS
Conformation of Product	Visually, functionally inspected per applicable product drawing.	No evidence of damage	PASS
Solder ability	IEC 60068-2-54 Solder temp. 255 ± 5 °C Immersion time: 5 ± 0.5 sec.	No evidence of damage	PASS

5. 結論 (Conclusion):

☒ 判定合格, 樣品滿足產品規格.

☒ Pass, The Sample meet Product Specification

☐ 判定不合格, 樣品不滿足產品規格,

☐ Reject, The Sample NOT meet Product Specification

備 註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;
Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval) JE Long 審核(Check): Sean Long 測試(Test): Joe Bai

測試報告

Reliability Test Report

測試編號/Test NO.: **RC16102801**

產品規格/Part Name: **1.5H PUSH LEVER Nano SI** 產品料號/Part NO.: **S1PL-150006-29G(S6)**

送檢日期/Send Date: **2016-10-27**

送檢部門/Require Dep't: **工程部**

測試部門/Test Dep't: **品保部**

測試時間/Test Date: **2016-10-28**

1. 測試說明 Test requirement and condition

測試項目 / Test item	項次/Item	參數/Parameter
端子正向力測試	溫度/Temperature	25°C
	濕度/Humidity	25% ~ 75%
	測試組別/Group NO.	A
	樣品數量/Sample Q'ty	5 Pcs

2. 測試方法與結果 Test Methods & Result

2.1 測試目的與要求(Test Purpose & Requirements):

目的: 客戶需求

要求: 根據規格書要求

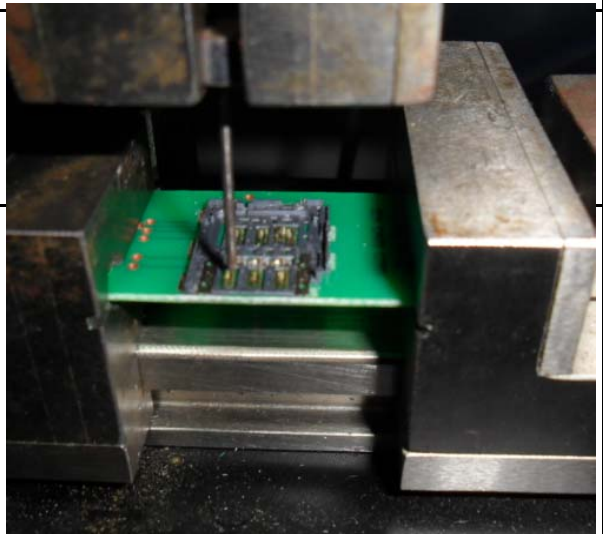
2.2 測試設備(Test Equipment):

自动插拔力测试机

2.3 測試方法(Test Methods):

- 測試根據客戶提供產品規格書進行測試,
- 测试速度: 25±3mm/min
- 测试头将端子弹高下压到离塑胶面0.1mm位置

2.4 測試結果(Test Result):



3. 結論 (Conclusion):

- ☒ 判定合格, 測試滿足產品規格.
- ☒ Pass, The results meet the requirements.
- ☐ 判定不合格, 測試不滿足產品規格,
- ☐ Reject, The results do not meet the requirements.

備 註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): **Jean Long**

審核(Check): **白文橋**

測試(Test): **羅建菊**

測試報告

Reliability Test Report

測試編號/Test NO.: **RC16102802**

產品規格/Part Name: **1.5H PUSH LEVER Nano SI**

產品料號/Part NO.: **S1PL-150006-29G(S6)**

送檢日期/Send Date: **2016-10-27**

送檢部門/Require Dep't: **工程部**

測試部門/Test Dep't: **品保部**

測試時間/Test Date: **2016-10-28**

1. 測試說明 Test requirement and condition

測試項目 / Test item	項次/Item	參數/Parameter
卡托插拔力測試	溫度/Temperature	25°C
	濕度/Humidity	25% ~ 75%
	測試組別/Group NO.	B
	樣品數量/Sample Q'ty	5 Pcs

2. 測試方法與結果 Test Methods & Result

2.1 測試目的與要求(Test Purpose & Requirements):

目的: 客戶需求

要求: 根據規格書要求

2.2 測試設備(Test Equipment):

自动插拔力测试机

2.3 測試方法(Test Methods):

1. 測試根據客戶提供產品規格書進行測試,
2. 测试速度:25±3mm/min

2.4 測試結果(Test Result):



3. 結論 (Conclusion):

- ☒ 判定合格, 測試滿足產品規格.
- ☒ Pass, The results meet the requirements.
- ☐ 判定不合格, 測試不滿足產品規格,
- ☐ Reject, The results do not meet the requirements.

備註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): **Jean Long**

審核(Check): **白文橋**

測試(Test): **羅建菊**

測試報告

Reliability Test Report

測試編號/Test NO.: **RC16102802**

產品規格/Part Name: **1.5H PUSH LEVER Nano SI**

產品料號/Part NO.: **S1PL-150006-29G(S6)**

送檢日期/Send Date: **2016-10-27**

送檢部門/Require Dep't: **工程部**

測試部門/Test Dep't: **品保部**

測試時間/Test Date: **2016-10-28**

1. 測試說明 Test requirement and condition

測試項目 / Test item	項次/Item	參數/Parameter
頂杆推力測試	溫度/Temperature	25°C
	濕度/Humidity	25% ~ 75%
	測試組別/Group NO.	B
	樣品數量/Sample Q'ty	5 Pcs

2. 測試方法與結果 Test Methods & Result

2.1 測試目的與要求(Test Purpose & Requirements):

目的: 客戶需求

要求: 根據規格書要求

2.2 測試設備(Test Equipment):

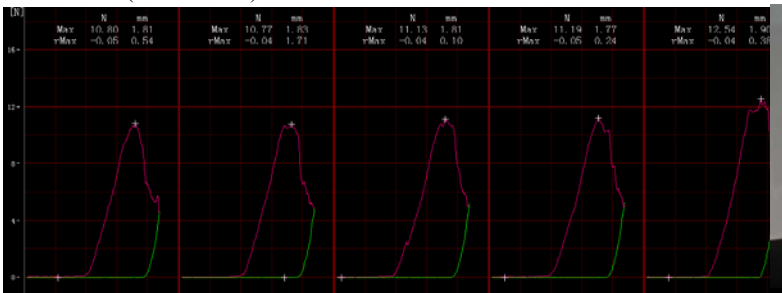
自動插拔力測試機

2.3 測試方法(Test Methods):

1. 測試根據客戶提供產品規格書進行測試,

2. 測試速度:25±3mm/min

2.4 測試結果(Test Result):



3. 結論 (Conclusion):

- ☒ 判定合格, 測試滿足產品規格.
- ☒ Pass, The results meet the requirements.
- ☐ 判定不合格, 測試不滿足產品規格,
- ☐ Reject, The results do not meet the requirements.

備註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): **Jean Long**

審核(Check): **白文橋**

測試(Test): **羅建菊**

測試報告

Reliability Test Report

測試編號/Test NO.: **RC16102901**

產品規格/Part Name: **1.5H PUSH LEVER Nano SI**

產品料號/Part NO.: **S1PL-150006-29G(S6)**

送檢日期/Send Date: **2016-10-27**

送檢部門/Require Dep't: **工程部**

測試部門/Test Den't: **品保部**

測試時間/Test Date: **2016-10-29**

1. 測試說明 Test requirement and condition

測試項目 / Test item	項次/Item	參數/Parameter
顶杆强度測試	溫度/Temperature	25°C
	濕度/Humidity	25% ~ 75%
	測試組別/Group NO.	C
	樣品數量/Sample Q'ty	5 Pcs

2. 測試方法與結果 Test Methods & Result

2.1 測試目的與要求(Test Purpose & Requirements):

目的: 客戶需求

要求: 根據規格書要求

2.2 測試設備(Test Equipment):

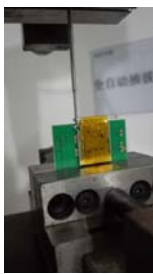
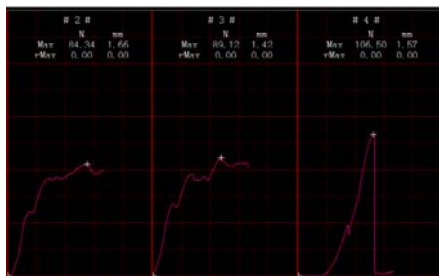
自动插拔力测试机

2.3 測試方法(Test Methods):

1. 測試根據客戶提供產品規格書進行測試,

2. 测试速度:25±3mm/min

2.4 測試結果(Test Result):



3. 結論 (Conclusion):

- ☒ 判定合格, 測試滿足產品規格.
- ☒ Pass, The results meet the requirements.
- ☐ 判定不合格, 測試不滿足產品規格,
- ☐ Reject, The results do not meet the requirements.

備 註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): **Jean Long**

審核(Check): **白文橋**

測試(Test): **羅建菊**

測試報告

Reliability Test Report

測試編號/Test NO: **RC16102802**

產品規格/Part Name: **1.5H PUSH LEVER Nano SI**

產品料號/Part NO: **S1PL-150006-29G(S6)**

送檢日期/Send Date: **2016-10-27**

送檢部門/Require Dep't: **工程部**

測試部門/Test Dep't: **品保部**

測試時間/Test Date: **2016-10-28**

1. 測試說明 Test requirement and condition

測試項目 / Test item	項次/Item	參數/Parameter
焊接强度測試	溫度/Temperature	25°C
	濕度/Humidity	25% ~ 75%
	測試組別/Group NO.	B
	樣品數量/Sample Q'ty	5 Pcs

2. 測試方法與結果 Test Methods & Result

2.1 測試目的與要求(Test Purpose & Requirements):

目的: 客戶需求

要求: 根據規格書要求

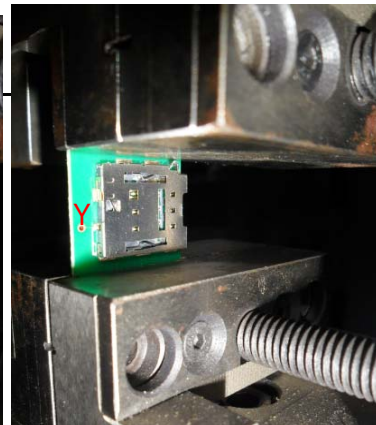
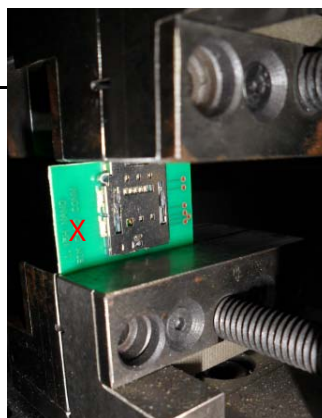
2.2 測試設備(Test Equipment):

自动插拔力测试机

2.3 測試方法(Test Methods):

1. 測試根據客戶提供產品規格書進行測試,
2. 测试速度:25±3mm/min

2.4 測試結果(Test Result):



3. 結論 (Conclusion):

- ☒ 判定合格, 測試滿足產品規格.
- ☒ Pass, The results meet the requirements.
- ☐ 判定不合格, 測試不滿足產品規格,
- ☐ Reject, The results do not meet the requirements.

備註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): **Jean Long**

審核(Check): **白文橋**

測試(Test): **羅建菊**

測試報告

Reliability Test Report

測試編號/Test NO: **RC16103101**

產品規格/Part Name: **1.5H PUSH LEVER Nano SI**

產品料號/Part NO: **S1PL-150006-29G(S6)**

送檢日期/Send Date: **2016-10-27**

送檢部門/Require Dep't: **工程部**

測試部門/Test Dep't: **品保部**

測試時間/Test Date: **2016-10-31**

1. 測試說明 Test requirement and condition

測試項目 / Test item	項次/Item	參數/Parameter
高溫回焊測試	溫度/Temperature	25°C
	濕度/Humidity	25% ~ 75%
	測試組別/Group NO.	H
	樣品數量/Sample Q'ty	5 Pcs

2. 測試方法與結果 Test Methods & Result

2.1 測試目的與要求(Test Purpose & Requirements):

目的: 客戶需求

要求: 根據客戶客戶規格書要求

2.2 測試設備(Test Equipment):

LEAD-FREE SM-S500 回焊爐

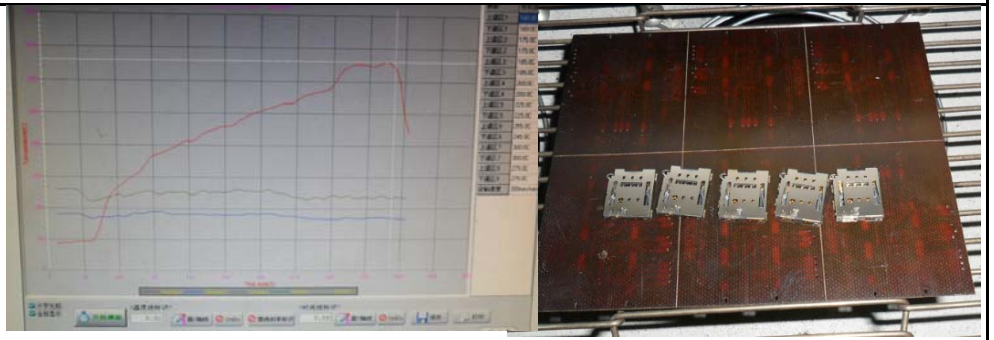
2.3 測試方法(Test Methods):

- 測試根據客戶提供產品規格書進行測試,參考標準EIA-364-56;
- 回焊曲線最高溫度: 265°C;
- 回焊最高溫度持續時間: 10 Sec



2.4 測試結果(Test Result):

- 產品無變形, 破壞, 起泡等不良;
- 產品導通測試確認導通;



3. 結論 (Conclusion):

- ☒ 判定合格, 測試滿足產品規格.
- ☒ Pass, The results meet the requirements.
- ☐ 判定不合格, 測試不滿足產品規格,
- ☐ Reject, The results do not meet the requirements.

備註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): **Jean Long**

審核(Check): **白文橋**

測試(Test): **羅建菊**

測試報告

Reliability Test Report

產品規格/Part Name: 1.5H PUSH LEVER Nano SI 產品料號/Part NO.: S1PL-150006-29G(S6) 測試編號/Test NO.: RC16103101
送檢部門/Require Dep't: 工程部 測試部門/Test Dep't: 品保部 送檢日期/Send Date: 2016-10-27
測試時間/Test Date: 2016-10-31

1. 測試說明 Test requirement and condition

測試項目 / Test item	項次/Item	參數/Parameter
粘 锡 測 試	溫度/Temperature	25°C
	濕度/Humidity	25% ~ 75%
	測試組別/Group NO.	H
	樣品數量/Sample Q'ty	5 Pcs

2. 測試方法與結果 Test Methods & Result

2.1 測試目的與要求(Test Purpose & Requirements):

目的: 客戶需求

要求: 根據客戶客戶規格書要求

2.2 測試設備(Test Equipment):

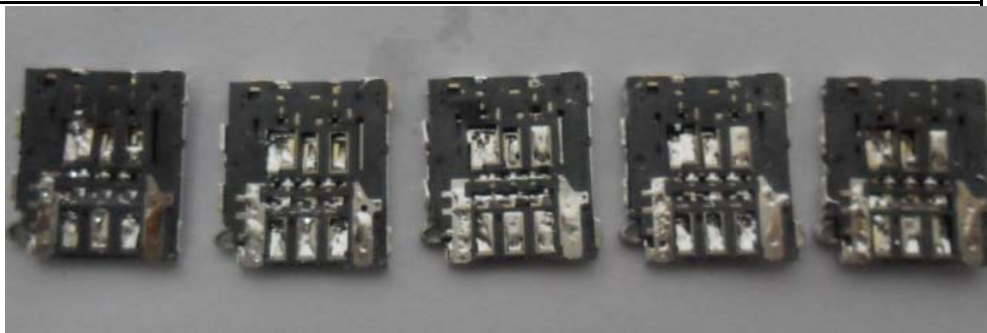
无铅锡炉 BD-50CA

2.3 測試方法(Test Methods):

- 測試根據客戶提供產品規格書進行測試,參考標準EIA-364-56;
- 回焊曲線最高溫度: 265°C ;
- 回焊最高溫度持續時間: 10 Sec

2.4 測試結果(Test Result):

- 產品無變形, 破壞, 起泡等不良;
- 產品導通測試確認導通;



3. 結論 (Conclusion):

- ☒ 判定合格, 測試滿足產品規格.
☒ Pass, The results meet the requirements.
☐ 判定不合格, 測試不滿足產品規格,
☐ Reject, The results do not meet the requirements.

備 註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): Jean Long

審核(Check): 白文橋

測試(Test): 羅建菊

測試報告

Reliability Test Report

測試編號/Test NO.: **RC16103001**

產品規格/Part Name: **1.5H PUSH LEVER Nano SI**

產品料號/Part NO.: **S1PL-150006-29G(S6)**

送檢日期/Send Date: **2016-10-27**

送檢部門/Require Dep't: **工程部**

測試部門/Test Dep't: **品保部**

測試時間/Test Date: **2016-10-30**

1. 測試說明 Test requirement and condition

測試項目 / Test item	項次/Item	參數/Parameter
盐 雾 測 試	溫度/Temperature	25°C
	濕度/Humidity	25% ~ 75%
	測試組別/Group NO.	G
	樣品數量/Sample Q'ty	5 Pcs

2. 測試方法與結果 Test Methods & Result

2.1 測試目的與要求(Test Purpose & Requirements):

目的: 客戶需求

要求: 根據客戶客戶規格書要求

2.2 測試設備(Test Equipment):

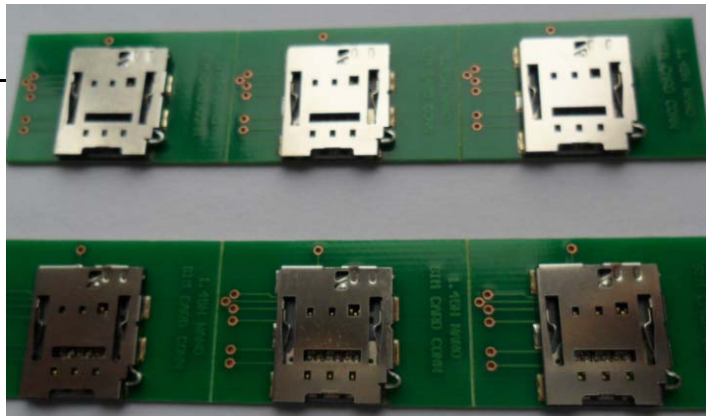
QIKE 盐雾测试机

2.3 測試方法(Test Methods):

1. 測試根據客戶提供產品規格書進行測試;
2. NaCl盐水浓度: 5±1%, 測試箱溫度: 35±3°C;
- 3 持续时间: 48HR

2.4 測試結果(Test Result):

- 1.產品功能面无氧化生锈;



3. 結論 (Conclusion):

- ☒ 判定合格, 測試滿足產品規格.
- ☒ Pass, The results meet the requirements.
- ☐ 判定不合格, 測試不滿足產品規格,
- ☐ Reject, The results do not meet the requirements.

備 註: 1. 測試結論只對投測樣品負責, 不保證批次產品的一致性;

Remark: 1. The Conclusion only responsible for investment, not to ensure the consistency of the batch production of products.

核定(Approval): **Jean Long**

審核(Check): **白文橋**

測試(Test): **羅建菊**